
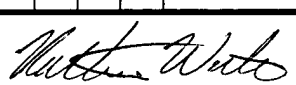
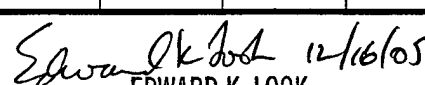


Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/824,922	LEE ET AL.	
	Examiner	Art Unit	
	Nathan Wiehe	3745	

ISSUE CLASSIFICATION									
ORIGINAL					CROSS REFERENCE(S)				
CLASS		SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)			
416		97R							
INTERNATIONAL CLASSIFICATION									
F	0	1	D	5/18					
				/					
				/					
				/					
				/					

 (Assistant Examiner) 12/13/05 (Date)	 EDWARD K. LOOK SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 3700 (Primary Examiner) 12/16/05 (Date)	Total Claims Allowed: 22 <table border="1"> <tr> <td>O.G. Print Claim(s)</td> <td>O.G. Print Fig.</td> </tr> <tr> <td>1</td> <td>2</td> </tr> </table>	O.G. Print Claim(s)	O.G. Print Fig.	1	2
O.G. Print Claim(s)	O.G. Print Fig.					
1	2					

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant						<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original
1	1		31		61		91		121		151
2	2		32		62		92		122		152
3	3		33		63		93		123		153
4	4		34		64		94		124		154
5	5		35		65		95		125		155
6	6		36		66		96		126		156
7	7		37		67		97		127		157
8	8		38		68		98		128		158
9	9		39		69		99		129		159
10	10		40		70		100		130		160
11	11		41		71		101		131		161
12	12		42		72		102		132		162
13	13		43		73		103		133		163
14	14		44		74		104		134		164
15	15		45		75		105		135		165
16	16		46		76		106		136		166
17	17		47		77		107		137		167
18	18		48		78		108		138		168
19	19		49		79		109		139		169
20	20		50		80		110		140		170
21	21		51		81		111		141		171
22	22		52		82		112		142		172
	23		53		83		113		143		173
	24		54		84		114		144		174
	25		55		85		115		145		175
	26		56		86		116		146		176
	27		57		87		117		147		177
	28		58		88		118		148		178
	29		59		89		119		149		179
	30		60		90		120		150		180